

Notice of References Cited	Application/Control No. 10/564,918	Applicant(s)/Patent Under Reexamination LEECH, LINDA	
	Examiner Junpeng Chen	Art Unit 2618	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,078,826 A	06-2000	Croft et al.	455/574
*	B	US-6,339,713 B1	01-2002	Hansson et al.	455/574
*	C	US-2002/0016189 A1	02-2002	Sheynblat et al.	455/574
*	D	US-6,345,180 B1	02-2002	Reichelt, Martin	455/404.1
*	E	US-2002/0065062 A1	05-2002	LEVESQUE, CHRISTIAN	455/343
*	F	US-6,408,196 B2	06-2002	Sheynblat et al.	455/574
*	G	US-6,571,091 B1	05-2003	Janssen et al.	455/343.1
*	H	US-2003/0104849 A1	06-2003	Arimitsu, Kazuhiro	455/574
*	I	US-2003/0144042 A1	07-2003	Weinfield et al.	455/574
*	J	US-2004/0137929 A1	07-2004	Jones et al.	455/517
*	K	US-7,010,365 B2	03-2006	Maymudes, David M.	700/65
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.